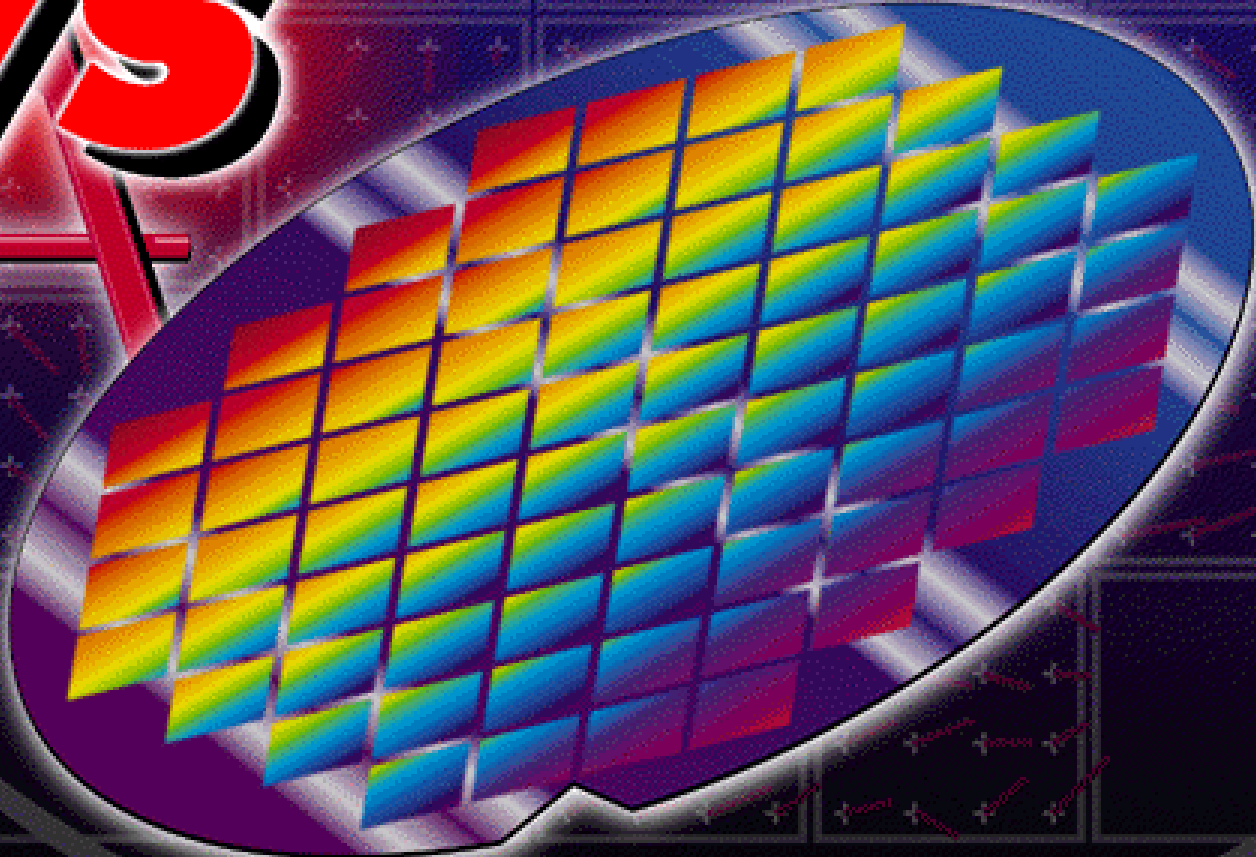


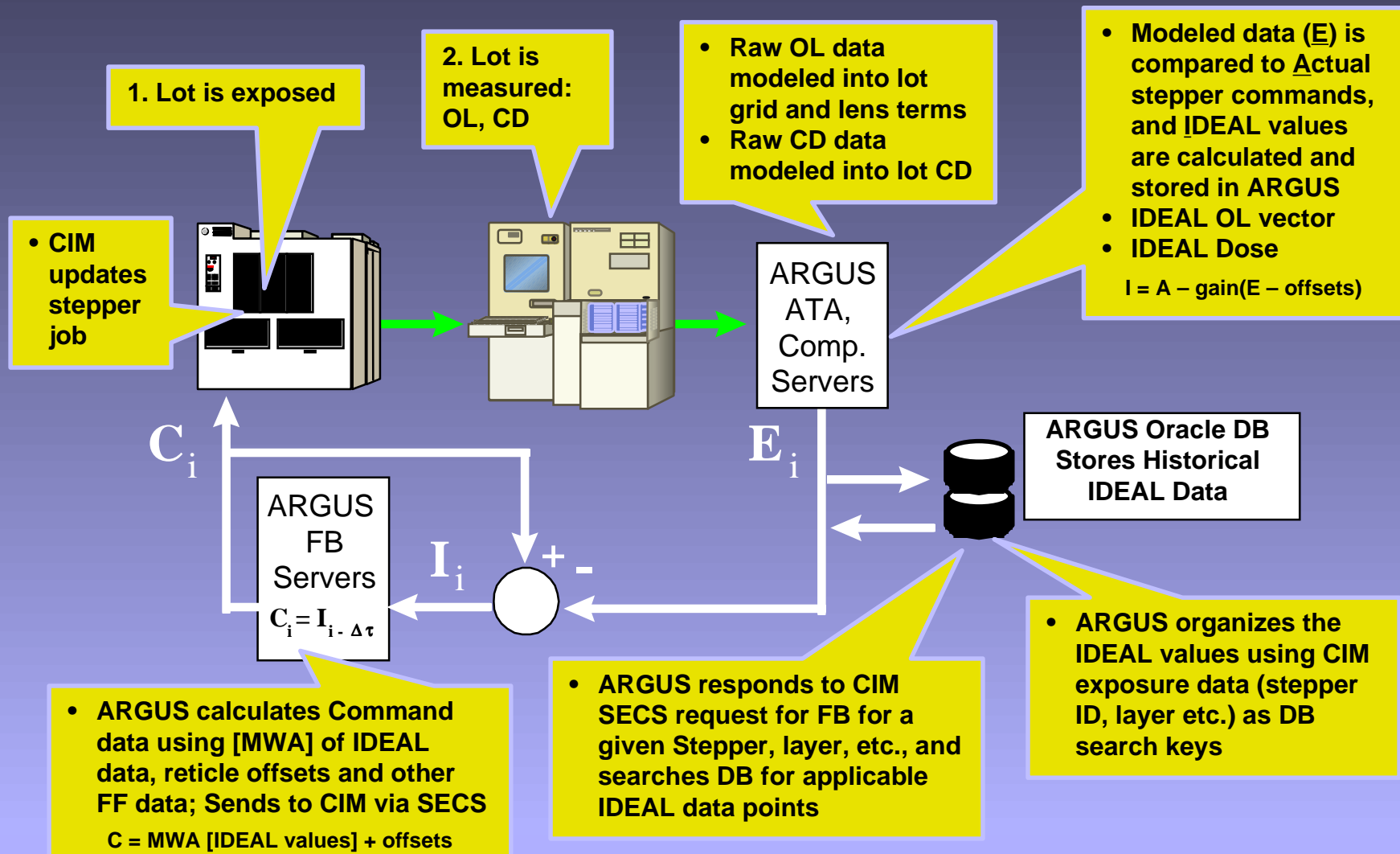
# NVS



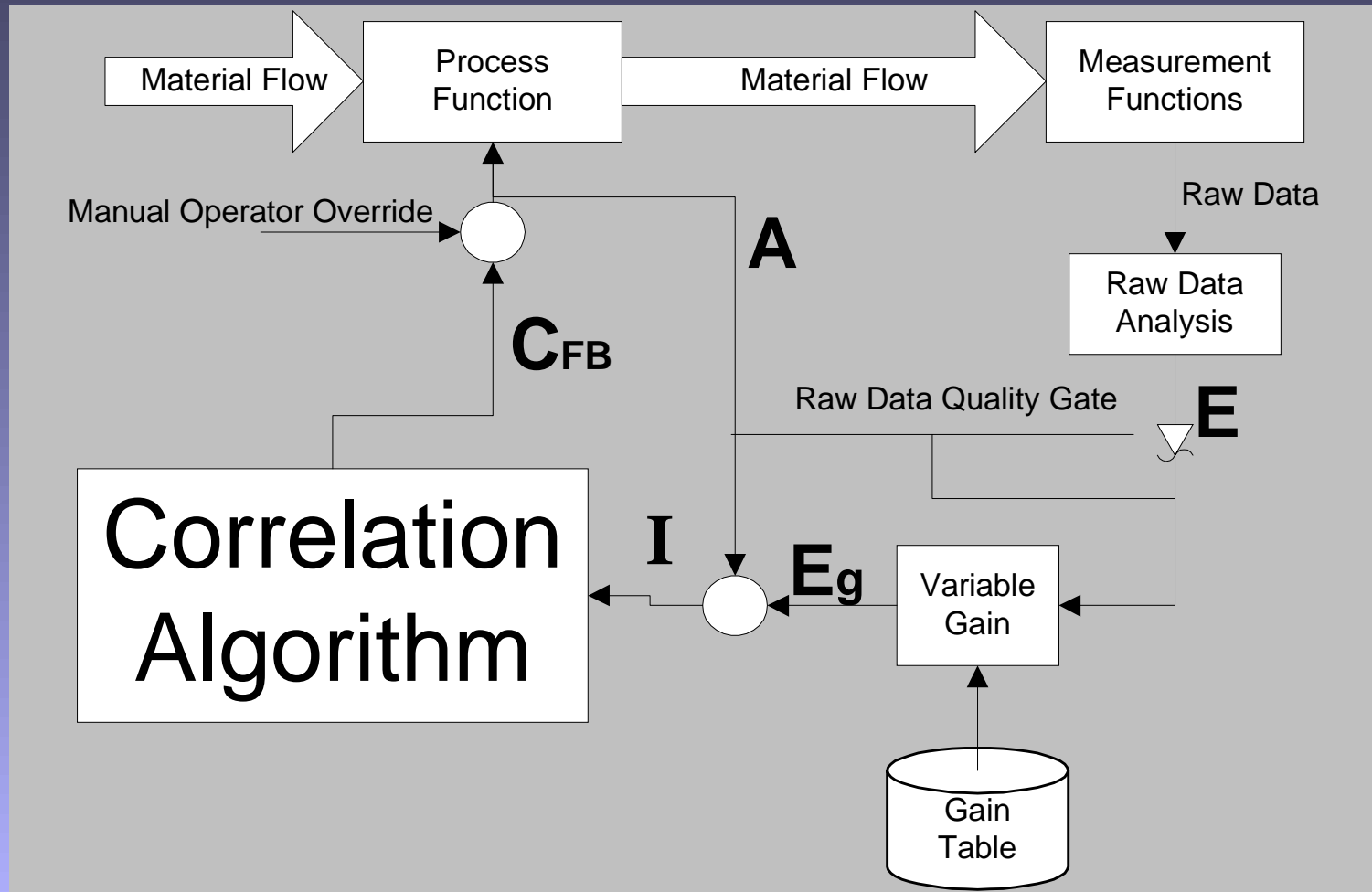
*Preliminary Report on the Effects  
of Metrology Time Delay on  
Run-to-Run Control*

October 2001 IMA Meeting

# ARGUS Run-to-Run Feedback Control



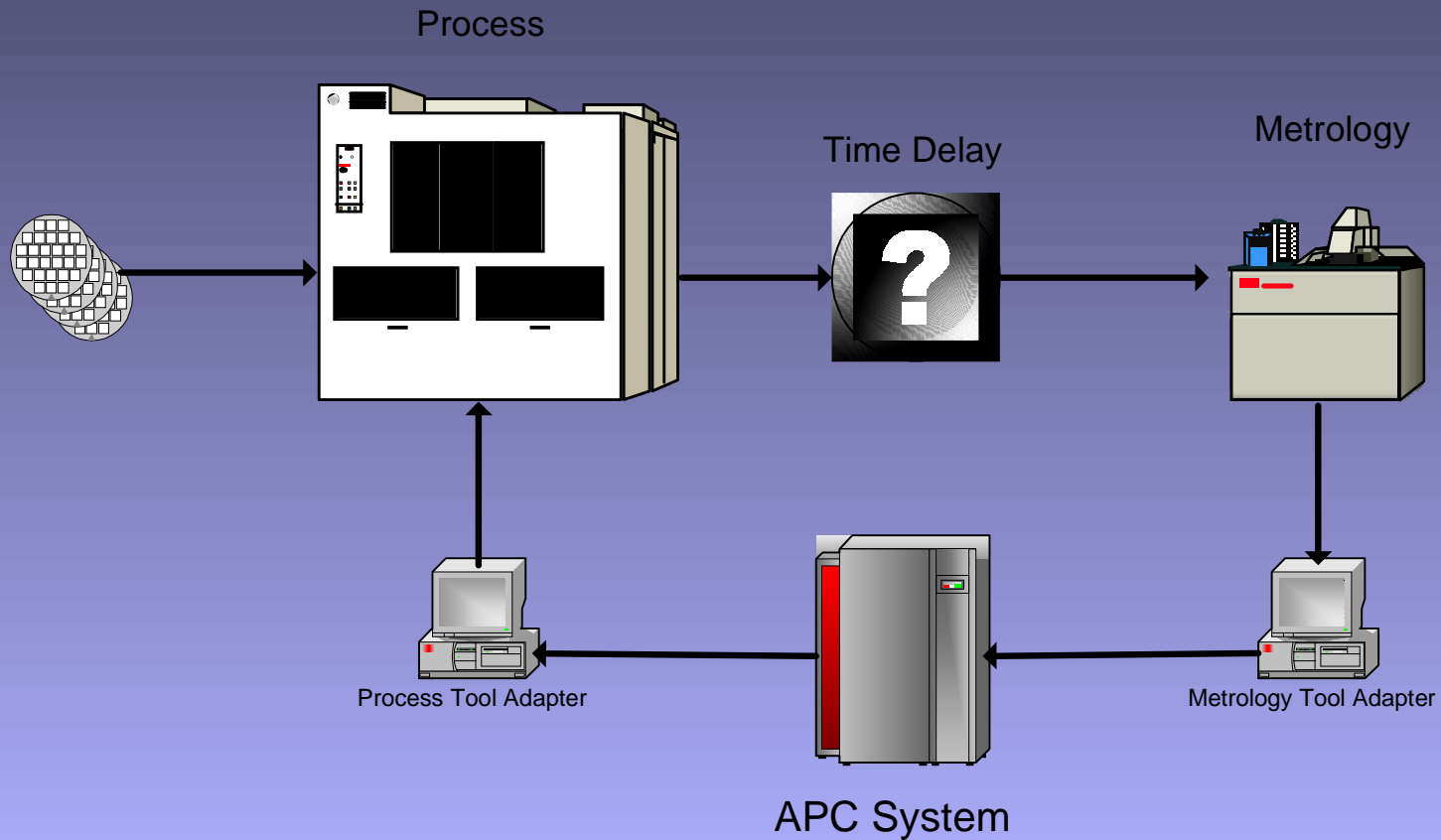
# Overview of Normal Feedback Control



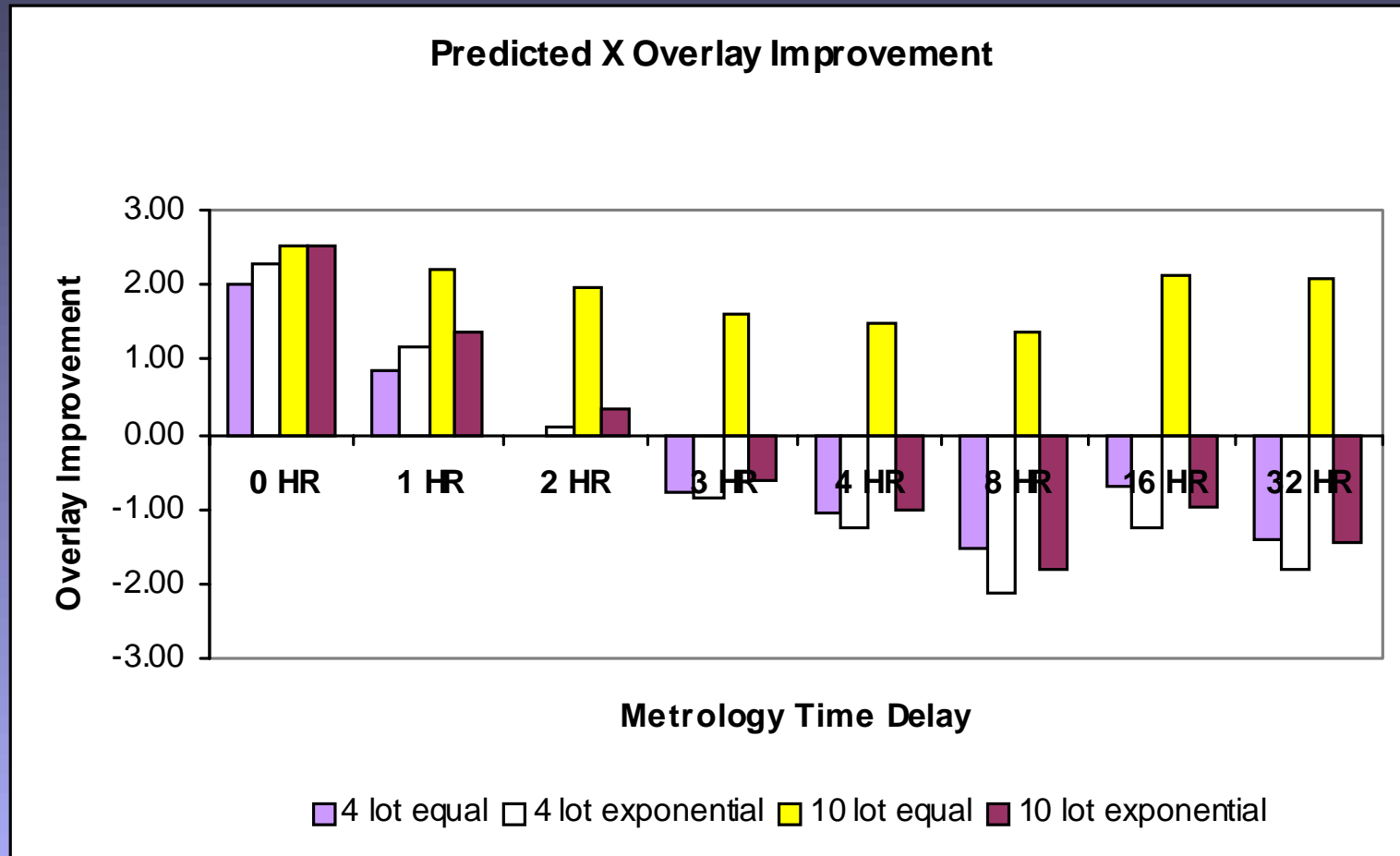
# *Examples of Some Possible Correlation Keys*

- Technology ID
- Exposure Tool ID
- Device ID
- Layer or Level ID
- Reticle or Mask ID
- Route ID
- Operation ID
-

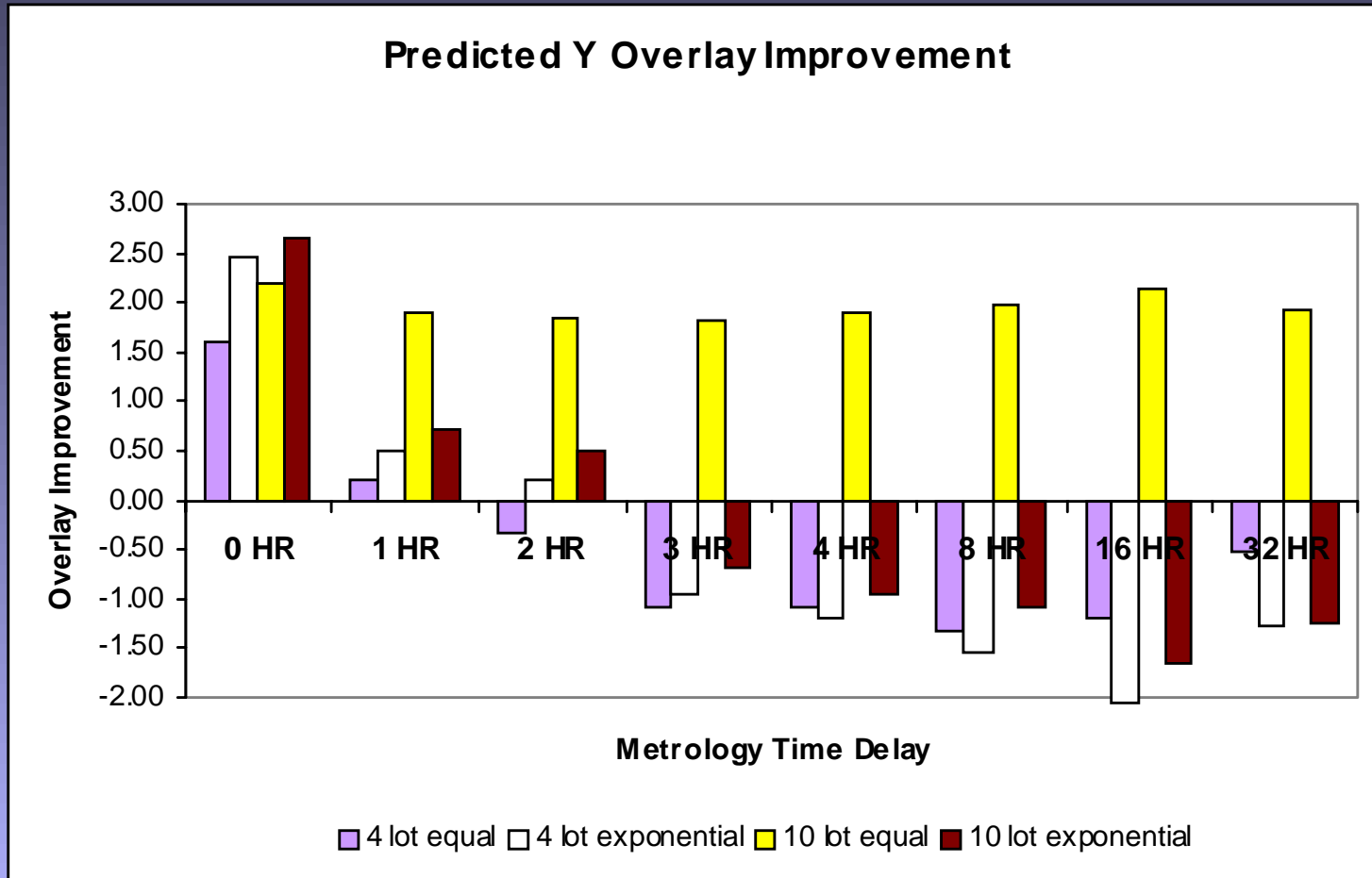
# Evaluation of the Effects of Time Delays



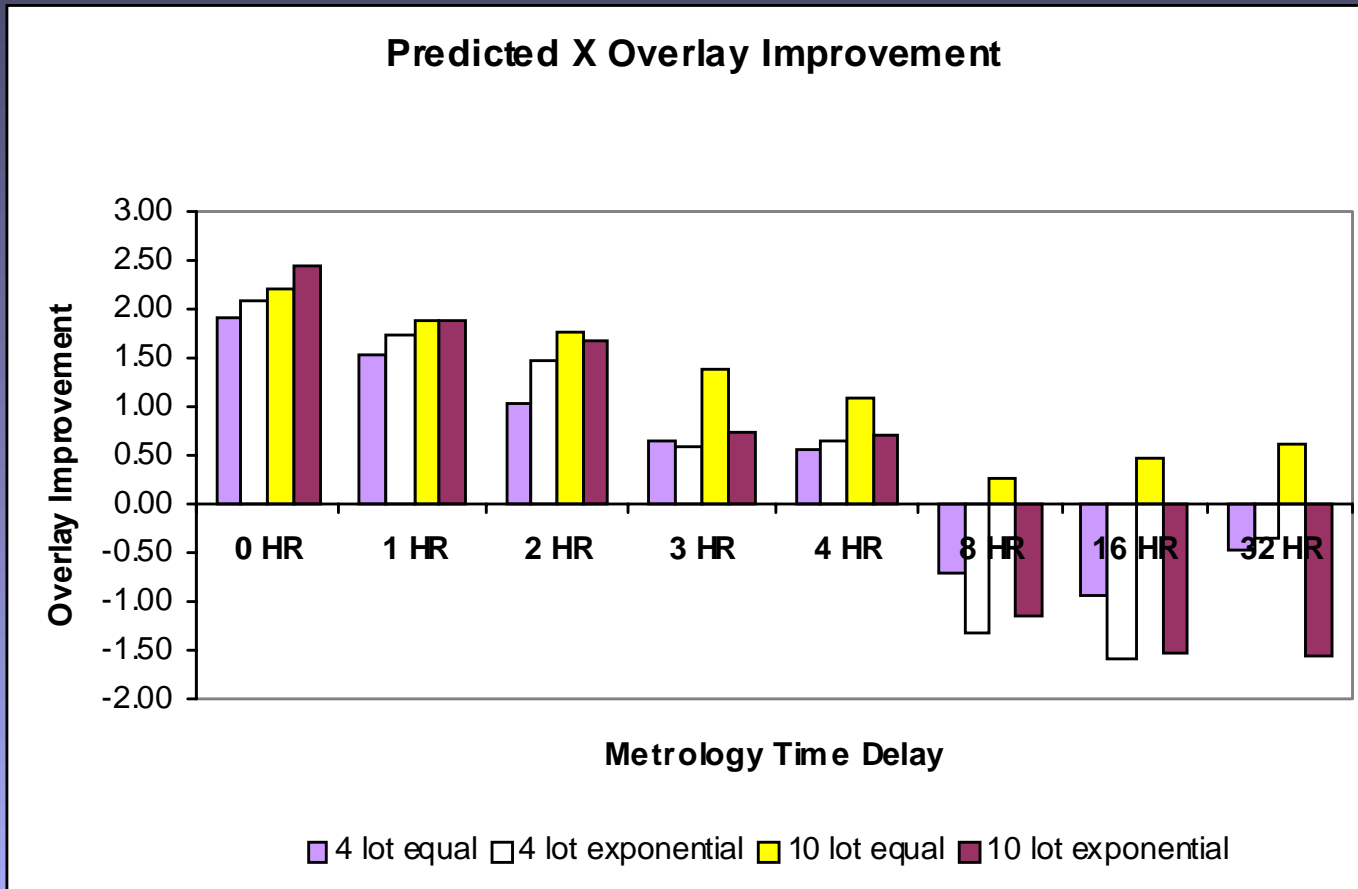
# Example 1: DUV A-B Matching (X)



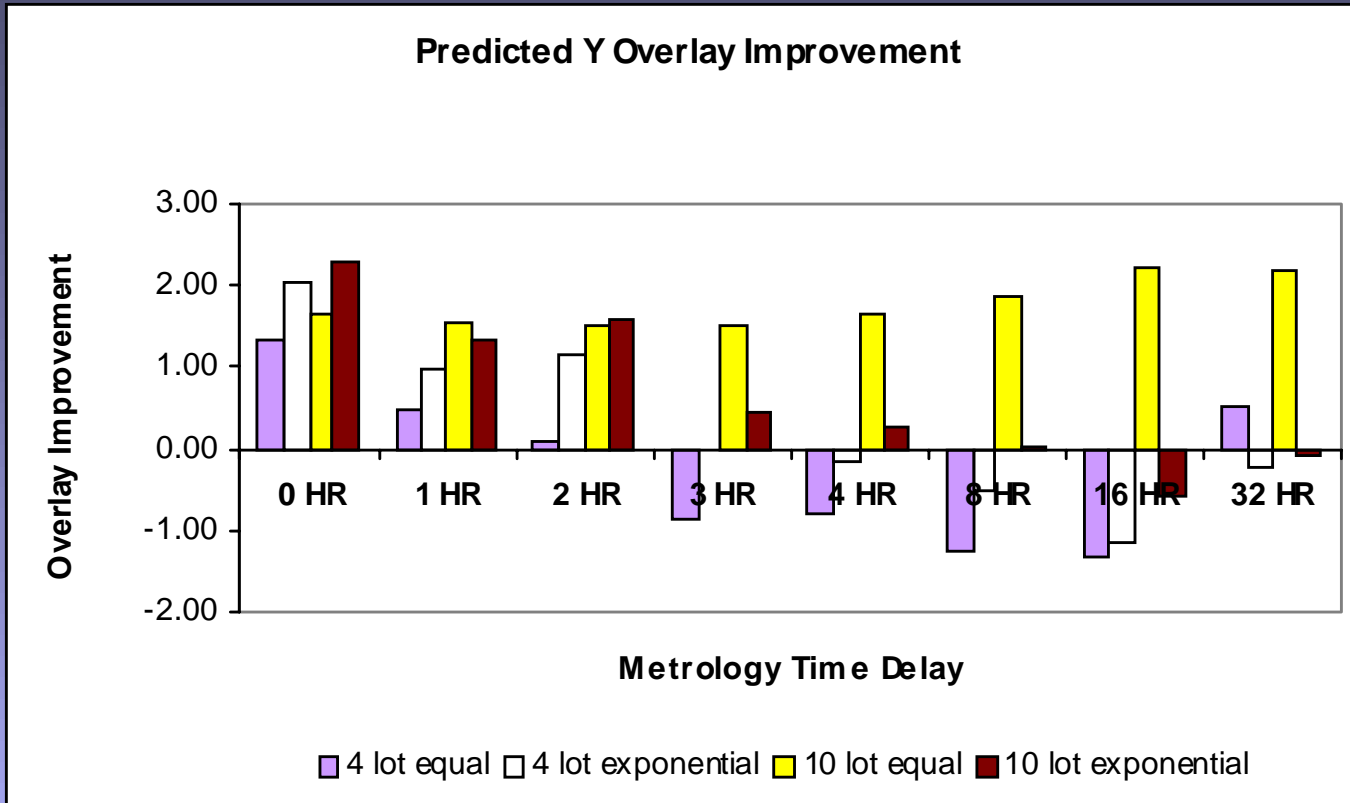
# Example 1: Y Overlay Error



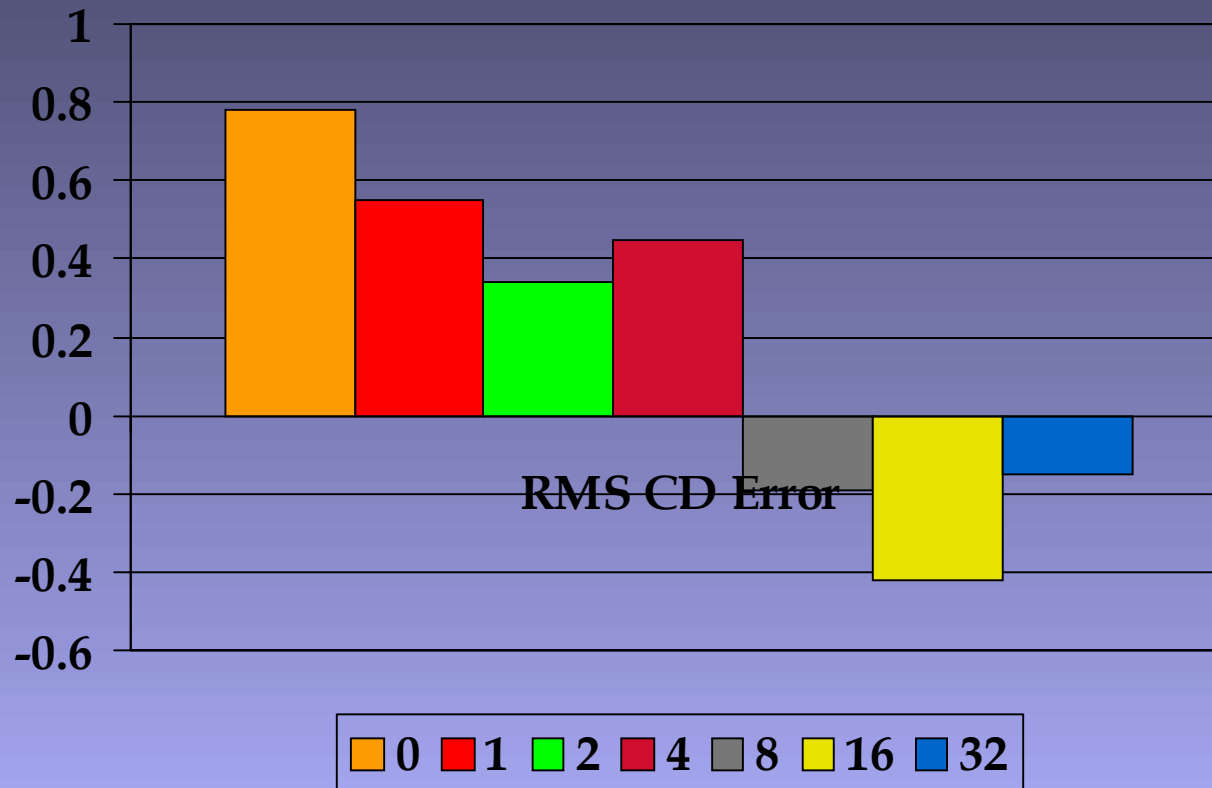
# Example 2: X Overlay Error



# Example 2: Y Overlay Error



# Example 3: RMS CD Error



*Using a 4 lot EWMA*